

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 251383US2CONT		SERIAL NO. 10/828,337 New-CONT Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Takashi YAMADA, et al.			
				FILING DATE Herein April 21, 2004		GROUP 2822	
				U.S. PATENT DOCUMENTS			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
IMS	AA	6,180,486	01/2001	Leobandung, et al.	438	405	
IMS	AB	6,214,653	04/2001	Chen, et al.	438	153	
IMS	AC	6,333,532	12/2001	Davari, et al.	257	301	
IMS	AD	6,350,653	02/2002	Adkisson, et al.	438	258	
IMS	AE	5,894,152	04/13/1999	M. A. JASO, et al.	257	347	
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
IMS	AO	10-303385	11/13/98	Japan (w/English Abstract)			x
IMS	AP	8-316431	11/29/96	Japan (w/English Abstract)			x
IMS	AQ	7-106434	04/21/95	Japan (w/English Abstract)			x
IMS	AR	11-238860	08/31/99	Japan (w/English Abstract)			x
IMS	AS	2000-91534	03/31/00	Japan (w/English Abstract)			x
IMS	AT	2000-243944	09/08/00	Japan (w/English Abstract)			x
IMS	AU	8-17694	01/19/96	Japan (w/English Abstract)			x
IMS	AV	11-17001	01/22/99	Japan (w/English Abstract)			x
IMS	AW	2000-269460	09/29/00	Japan (w/English Abstract)			x
IMS	AX	2001-196556	07/19/01	Japan (w/English Abstract)			x
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
IMS	AY	Robert HANNON, et al., 2000 Symposium on VLSI Technology Digest of Technical Papers, pages 66-67, "0.25 μ m MERGED BULK DRAM AND SOI LOGIC USING PATTERNED SOI", June 13, 2000					
IMS	AZ	M. SATO, et al., 2000 Symposium on VLSI Technology Digest of Technical Papers, pages 82-83, "TRANSISTOR ON CAPACITOR (TOC) CELL WITH QUARTER PITCH LAYOUT FOR 0.13 μ m DRAMS AND BEYOND", June 13, 2000					
					<input type="checkbox"/> Additional References sheet(s) attached		
Examiner <i>William E. Swanson</i>					Date Considered 10/18/06		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							